

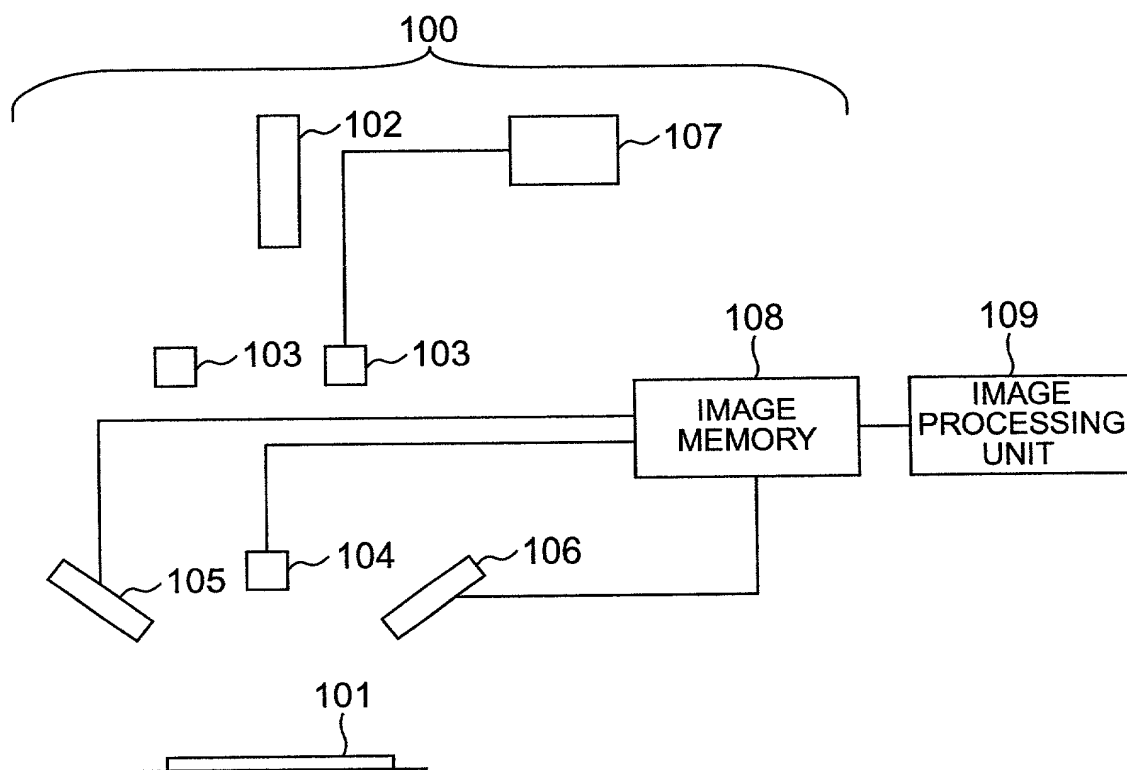
Applicant: Toshifumi Honda, et al.

Title: Defect Inspection Method

Atty Docket No. 16869S-043200

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FIG. 1



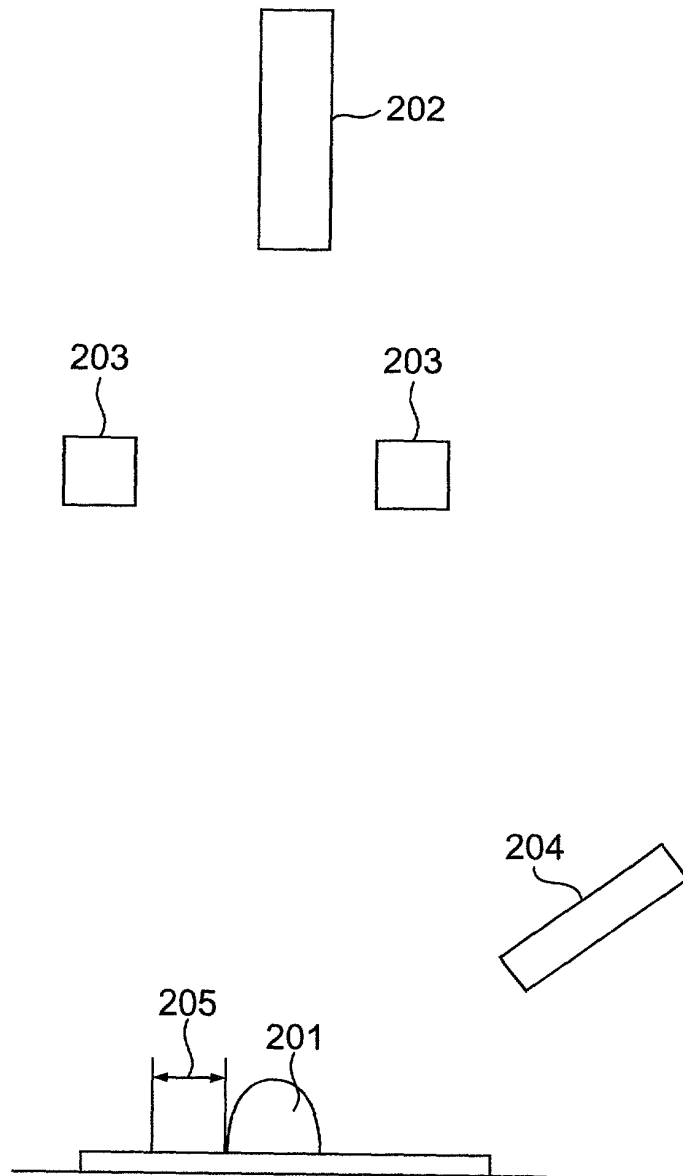
Applicant: Toshifumi Honda, et al.

Title: Defect Inspection Method

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FIG. 2



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FIG. 3

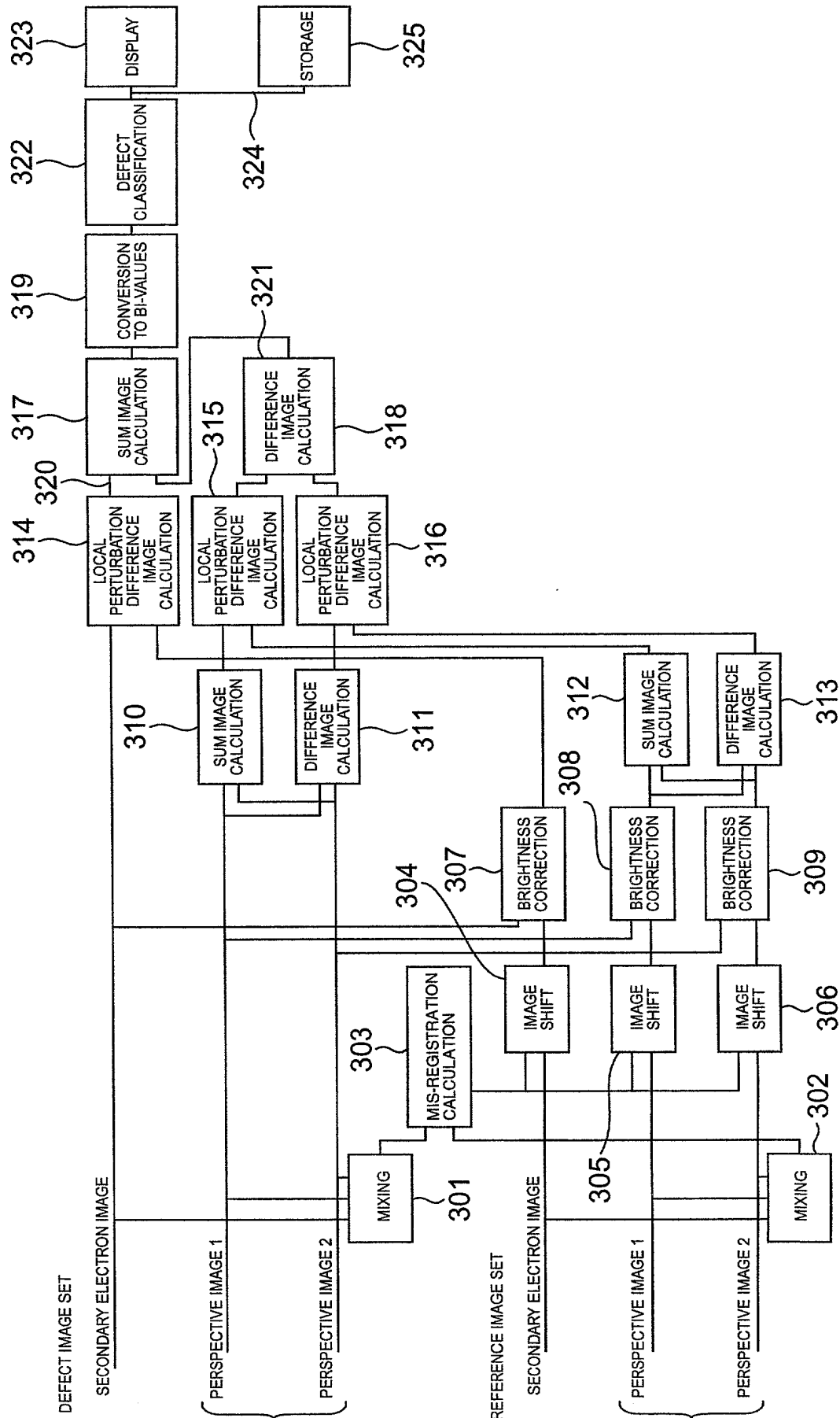


FIG. 4

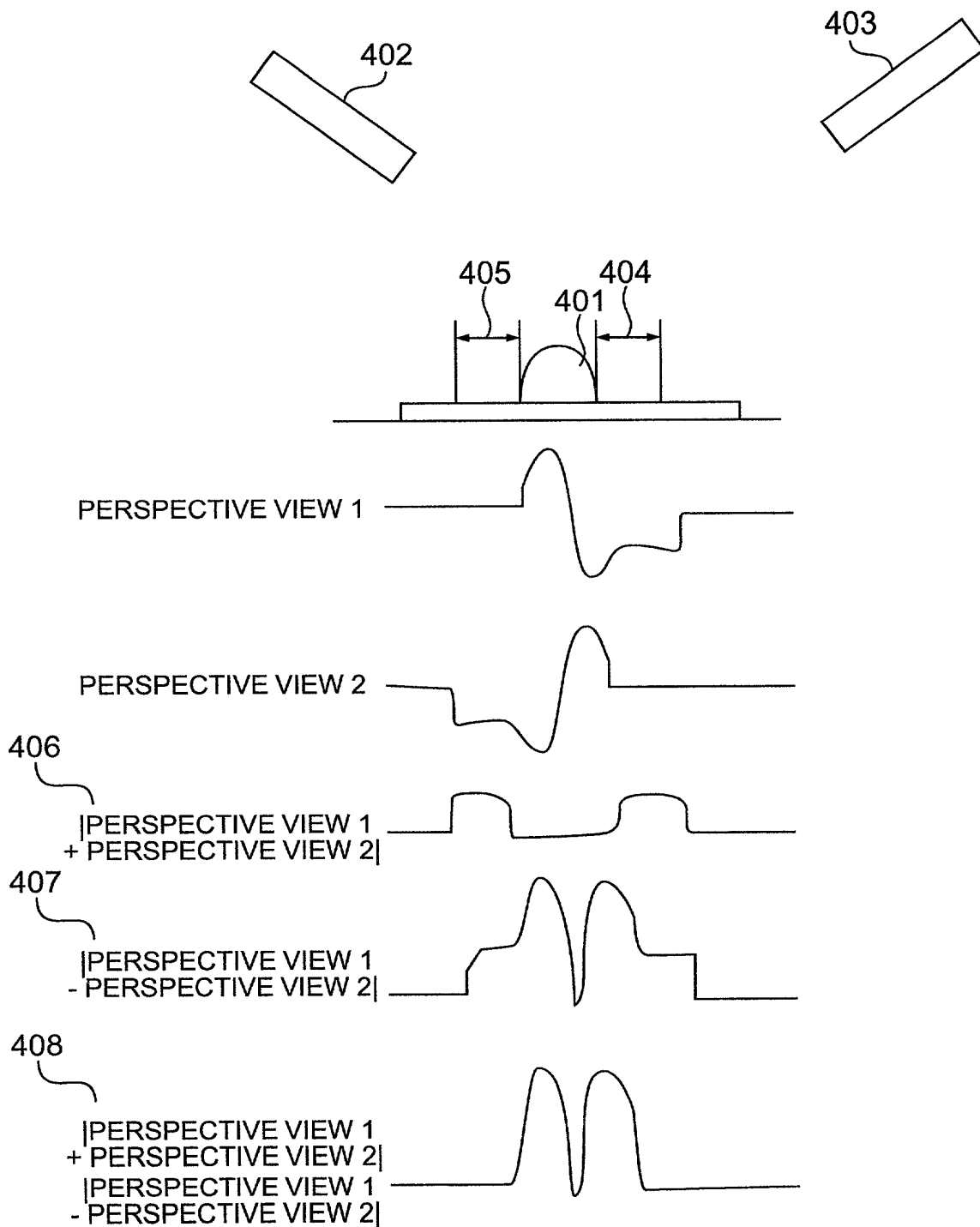
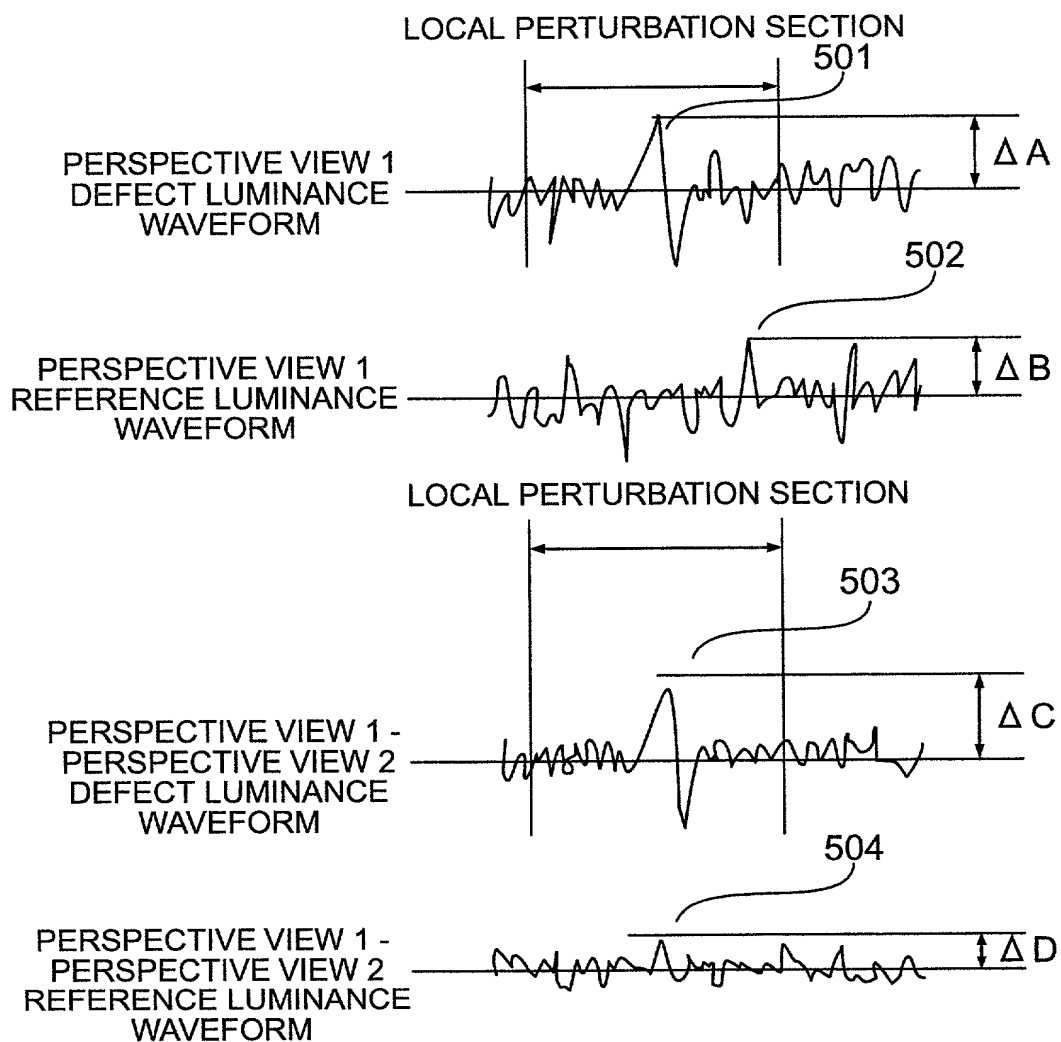


FIG. 5



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FIG. 6

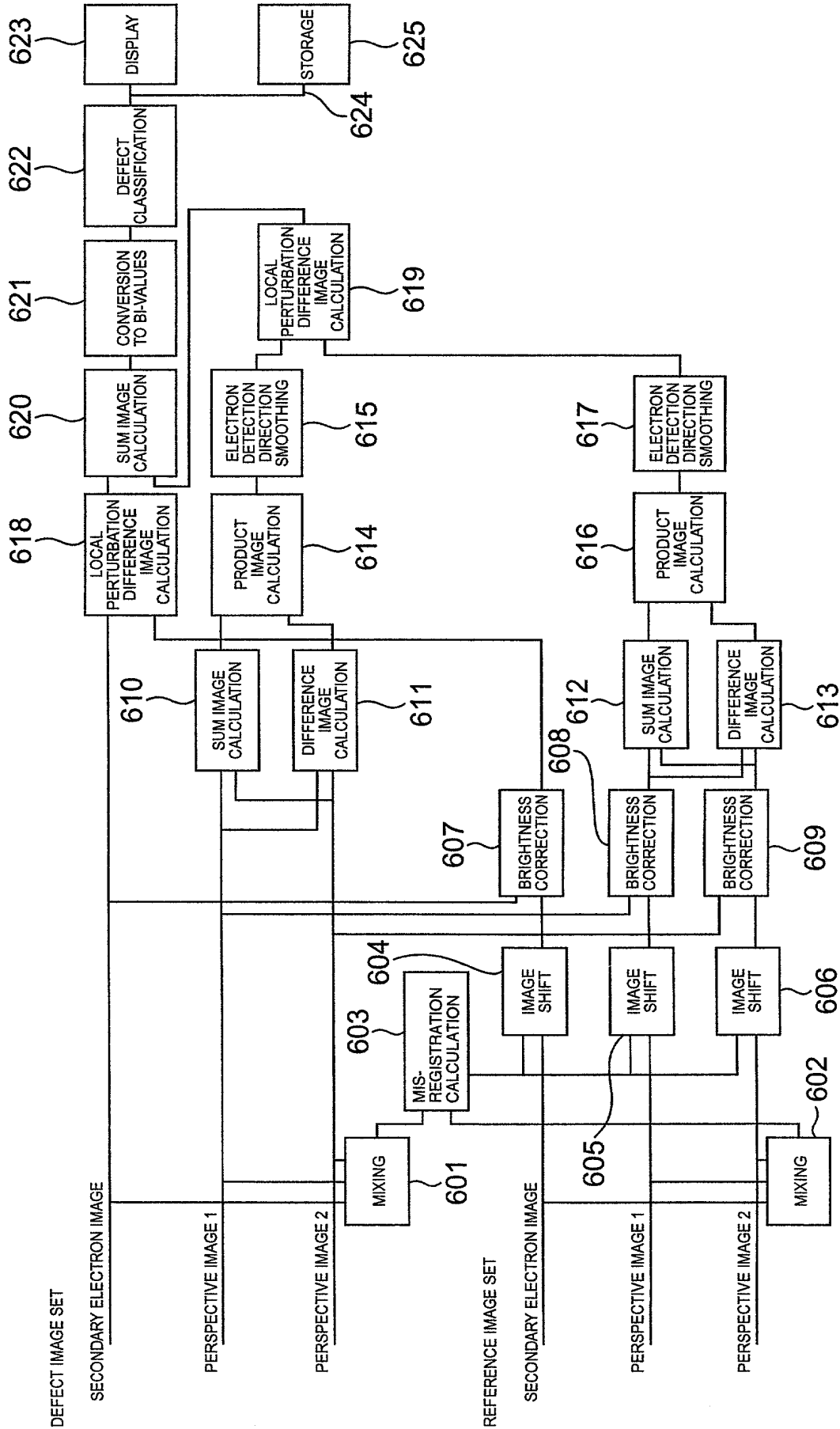
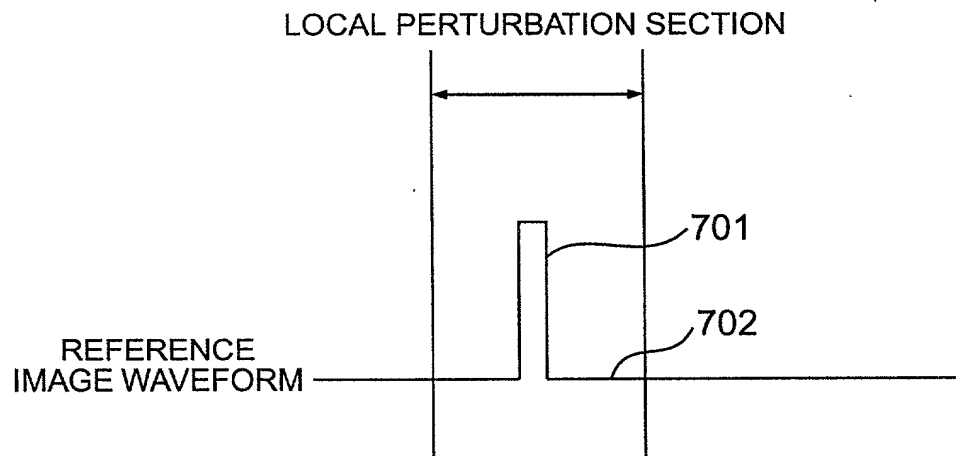


FIG. 7

DEFECT IMAGE WAVEFORM



LOCAL PERTURBATION
DIFFERENCE WAVEFORM